

Abstract Submitted  
for the MAR11 Meeting of  
The American Physical Society

**First-Principles Investigations of Oxygen Vacancies on SnO2 Nanofilms**<sup>1</sup> DANIEL CELLUCCI, STEVEN LEWIS, University of Georgia — The n-type semiconductor tin dioxide (SnO<sub>2</sub>) has long been used as the working material for robust, inexpensive oxidizable-gas sensors. In recent years, advances in nanofabrication have made possible the well-controlled formation of SnO<sub>2</sub> nanocrystals. Since gas sensing in SnO<sub>2</sub> involves changes in surface resistivity as a function of gas concentration, nanocrystalline SnO<sub>2</sub> holds great promise for high-sensitivity gas sensors, due to the high surface-to-volume ratio. A key feature of the sensing mechanism is the facile formation and destruction of oxygen vacancies at (or near) the surface. In this talk I will discuss our ongoing first-principles investigations of surface oxygen vacancies in SnO<sub>2</sub> nanofilms. We have focused on vacancy formation among the so-called bridging oxygen atoms on the (110) surface of rutile SnO<sub>2</sub>, as a function of vacancy concentration and film thickness, studying the effect on local atomic and electronic structure. This work is the first phase of a longer-term investigation of surface vacancy phases on SnO<sub>2</sub> (110) as a function of temperature and oxygen vapor pressure.

<sup>1</sup>National Science Foundation, Grant #CMMI-0856719.

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Date submitted: 23 Nov 2010

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